

Search Notes

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Examiner

Yong D. Pak

Applicant(s)/Patent under
Reexamination

CROTEAU ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no: 1 and 2	9/27/2007	YP
east: text and inventor search, see search history	9/27/2007	YP
PALM: inventor search, all inventors	9/27/2007	YP